



SAR Compliance Test Report

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Testing laboratory: TCC Nokia Beijing Laboratory Client: Nokia Corporation

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engineer: person:

 Tested device:
 RM-685

 FCC ID:
 0MNRM-685

 IC:

Supplement reports: SAR_Photo_RM-685_02

Testing has been carried 47CFR §2.1093

Measurements made by:

out in accordance with:

Radiofrequency Radiation Exposure Evaluation: Portable Devices

FCC OET Bulletin 65 (Edition 97-01), Supplement C (Edition 01-01)

Evaluating Compliance with FCC Guidelines for Human Exposure to Radiofrequency

Electromagnetic Fields

RSS-102

Liang Dong

Evaluation Procedure for Mobile and Portable Radio Transmitters with Respect to Health Canada's Safety Code 6 for Exposure of Humans to Radio Frequency Fields

IEEE 1528 - 2003

IEEE Recommended Practice for Determining the Peak Spatial-Average Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices:

Measurement Technique

Documentation: The documentation of the testing performed on the tested devices is archived for 15 years at

TCC Nokia.

Test results: The tested device complies with the requirements in respect of all parameters subject to the

test. The test results and statements relate only to the items tested. The test report shall not

be reproduced except in full, without written approval of the laboratory.

Date and signatures:

For the contents:





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Applicant: Nokia Corporation





1. SUMMARY OF SAR TEST REPORT

1.1 Test Details

Period of test	2010-03-18
SN, HW and SW numbers of	SN: A0000001C8FB23, HW: 1000, SW: WT_0100B07_TLC_0100T_R800,
tested device	DUT: 51193
Batteries used in testing	BL-4C, DUT: 51201, 51202, 51203
Headsets used in testing	HS-105, DUT: 51196
Other accessories used in	-
testing	
State of sample	Prototype unit
Notes	-

1.2 Maximum Results

The maximum measured SAR values for Head configuration and Body Worn configuration are given in section 1.2.1 and 1.2.2 respectively. The device conforms to the requirements of the standard(s) when the maximum measured SAR value is less than or equal to the limit.

1.2.1 Head Configuration

Mode	Ch / f (MHz)	Conducted power	Position	Measured SAR value (1g avg)	Scaled* SAR value (1g avg)	SAR limit (1g avg)	Result
CDMA800	384 / 836.52	24.12 dBm	Left, Cheek	0.838 W/kg	0.94 W/kg	1.6 W/kg	PASSED

1.2.2 Body Worn Configuration

Mode	Ch / f (MHz)	Conducted power	Separation distance	Measured SAR value (1g avg)	Scaled* SAR value (1g avg)	SAR limit (1g avg)	Result
CDMA800	1013 / 824.70	24.19 dBm	1.5 cm	1.04 W/kg	1.16 W/kg	1.6 W/kg	PASSED

^{*} SAR values are scaled up by 12% to cover measurement drift. As a consequence of this upwards correction of the SAR values, the contribution of measurement drift to the overall measurement uncertainty (Section 6) is reduced to zero.

1.2.3 Maximum Drift

Maximum drift covered by 12% scaling up of the SAR values	Maximum drift during measurements
0.5dB	0.36dB





1.2.4 Measurement Uncertainty

Expanded Uncertainty (k=2) 95% ± 25.8%
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2. DESCRIPTION OF THE DEVICE UNDER TEST

Device category	Portable
Exposure environment	General population / uncontrolled

Modes of Operation	Bands	Modulation Mode	Duty Cycle	Transmitter Frequency Range (MHz)
CDMA	800	QPSK	1	824 - 849

This is a CDMA 1 x RTT device.

2.1 Description of the Antenna

The device has an internal antenna for cellular use. The cellular antenna is located at the bottom underneath the back cover.

3. TEST CONDITIONS

3.1 Temperature and Humidity

Ambient temperature (°C):	21.0 to 22.0
Ambient humidity (RH %):	40 to 50

3.2 Test Signal, Frequencies and Output Power

The device was put into operation by using a call tester. Communication between the device and the call tester was established by air link.

The device output power was set to maximum power level for all tests; a fully charged battery was used for every test sequence.

In all operating bands the measurements were performed on lowest, middle and highest channels.





3.3 Test Cases and Test Minimisation

The tested device examined in this report may not incorporate all of the features described in the text that follows, but its SAR evaluation will have been subjected to the same considerations and test logic described below.

Whilst it's possible to identify the maximum SAR test cases from inspection of the conducted power levels given in the Results tables (Section 7), different modes in the same band and multi-slot transmit GSM/GPRS modes can create some difficulties. Therefore the sequence of the SAR tests made in evaluating this device has used test logic that is based on measured SAR values. Comparison of measured SAR values in this way, can also allow some test minimization (i.e. test elimination) to be made.

For example, when SAR testing multi-slot GSM/GPRS/EGPRS modes, it is an inefficient use of test resources to fully SAR test every test configuration in each of the different modes as these modes have a fixed power relationship between them that is the same, irrespective of the test configuration. In the case of multi-slot GSM/GPRS modes, a single comparative SAR test - using the same test channel and test configuration – is made in each of the n-slot modes; the mode with the highest measured SAR value is then subjected to full SAR testing in all test configurations. These comparative SAR tests (same frequency, same test configuration) are regarded as extremely accurate as they are relative tests in which the tested device changes neither its frequency nor its position between tests. For different modes that operate in the same band and use the same antenna e.g. GSM/GPRS850 and WCDMA850, full SAR testing is carried out in the GSM/GPRS850 mode but WCDMA850 testing is limited to 3 channel testing in the maximum SAR test configuration for GSM/GPRS850.

Multi-slot SAR testing against the Head is always performed whenever such a device offers Push to Talk over cellular with the internal earpiece active, Dual Transfer Mode (i.e. the ability to transmit voice and data simultaneously using the same transmitter) or has WLAN (which enables a Voice over IP call to take place whilst the device can simultaneously transmit data on a cellular band). Whenever a device has an intended multi-slot use against the head, it is also Head SAR tested in EGPRS mode. It should be noted that EGPRS transmit modes can have either GMSK or 8PSK modulation but, when tested, only 8PSK EGPRS will appear explicitly in the results tables, as GMSK EGPRS mode has identical time-averaged power to the reported GPRS mode.

Devices that have flips or slides are fully SAR tested in all device configurations consistent with their intended usage. For example, flip phones that can receive a call in closed mode are SAR tested against the head in both open and closed configurations. Similarly, slide phones are fully SAR tested in all slide configurations in which calls are intended to be made or received.

In the results tables in Section 7, the maximum SAR value for the 'basic' tests (i.e. left cheek, left tilt, right cheek and right tilt in Head SAR testing; with and without headset with the back &/or





display side facing the flat phantom in Body SAR testing) is bolded for each band. In some cases, after full testing of the basic SAR test configurations has been completed, additional checking SAR tests are made. These checking tests are always based on the bolded result from the 'basic' testing. When the SAR value of a checking test exceeds the maximum value from the basic tests, it is also bolded and used as the basis for any further checking tests that might be needed.

Checking tests are largely voluntary and can cover optional batteries, different camera slide positions, optional covers, etc. In the case of optional batteries, if the construction of the optional battery is significantly different to the battery used in the full testing e.g. if the outer can is floating electrically rather than grounded, then the maximum SAR test configuration in each band is tested with the optional battery in 3 channels. For camera slides, if the slide material is metal, then checking tests in 3 channels are again run for the maximum SAR test configuration in each band. For plastic camera slides, SAR checking is only carried out in the channel that provided the maximum SAR value for the original. Optional front and back covers are tested if their shape differs significantly from the original or if their metallic content varies by more than 15% from the original; in the former case, the testing depends on the extent of the physical differences, whereas in the latter case, 3 channel SAR testing is performed in every band in the max SAR test configuration..

4. DESCRIPTION OF THE TEST EQUIPMENT

4.1 Measurement System and Components

The measurements were performed using an automated near-field scanning system, DASY4, manufactured by Schmid & Partner Engineering AG (SPEAG) in Switzerland. The SAR extrapolation algorithm used in all measurements was the 'advanced extrapolation' algorithm.

The following table lists calibration dates of SPEAG components:

Test Equipment	Serial Number	Calibration interval	Calibration expiry
DAE 4	480	12 months	2010-09
E-field Probe ET3DV6	1652	12 months	2010-09
Dipole Validation Kit, D835V2	479	24 months	2011-02
DASY4 software	Version 4.7	-	-





Additional test equipment used in testing:

Test Equipment	Model	Serial Number	Calibration interval	Calibration expiry
Signal Generator	8648C	3847M00258	12 months	2010-05
Call Tester	Agilent 8960	GB43304340	-	-
Amplifier	AR 5SIG4M3	302339	12 months	2010-05
RF Network Analyzer	8753ES	My40002096	12 months	2010-05
Dielectric Probe Kit	85070C	01033717	-	-
Power Meter	Agilent E4419B	My41291520	12 months	2010-05
Power Sensor	Agilent 8482A	US37295411	12 months	2010-05

4.1.1 Isotropic E-field Probe Type ET3DV6

Construction Symmetrical design with triangular core

Built-in optical fiber for surface detection system

Built-in shielding against static charges

PEEK enclosure material (resistant to organic solvents, e.g., butyl

diglycol)

Calibration Calibration certificate in Appendix C

Frequency 10 MHz to 3 GHz (dosimetry); Linearity: ± 0.2 dB (30 MHz to 3 GHz)

Optical Surface Detection ± 0.2 mm repeatability in air and clear liquids over diffuse

reflecting surfaces

Directivity ± 0.2 dB in HSL (rotation around probe axis)

± 0.4 dB in HSL (rotation normal to probe axis)

Dynamic Range 5 μ W/g to > 100 mW/g; Linearity: \pm 0.2 dB

Dimensions Overall length: 330 mm

Tip length: 16 mm Body diameter: 12 mm Tip diameter: 6.8 mm

Distance from probe tip to dipole centers: 2.7 mm

Application General dosimetry up to 3 GHz

Compliance tests of mobile phones

Fast automatic scanning in arbitrary phantoms





4.2 Phantoms

The phantom used for all tests i.e. for both system checks and device testing, was the twinheaded "SAM Phantom", manufactured by SPEAG. The phantom conforms to the requirements of IEEE 1528 - 2003.

System checking was performed using the flat section, whilst Head SAR tests used the left and right head profile sections. Body SAR testing also used the flat section between the head profiles.

The SPEAG device holder (see Section 5.1) was used to position the device in all tests whilst a tripod was used to position the validation dipoles against the flat section of phantom.

4.3 Tissue Simulants

Recommended values for the dielectric parameters of the tissue simulants are given in IEEE 1528 - 2003 and FCC Supplement C to 0ET Bulletin 65. All tests were carried out using simulants whose dielectric parameters were within \pm 5% of the recommended values. All tests were carried out within 24 hours of measuring the dielectric parameters.

The depth of the tissue simulant was 15.0 \pm 0.5 cm measured from the ear reference point during system checking and device measurements.

4.3.1 Tissue Simulant Recipes

The following recipe(s) were used for Head and Body tissue simulant(s):

800MHz band

Ingredient	Head (% by weight)	Body (% by weight)
Deionised Water	39.74	55.97
HEC	0.25	1.21
Sugar	58.31	41.76
Preservative	0.15	0.27
Salt	1.55	0.79

4.3.2 System Checking

The manufacturer calibrates the probes annually. Dielectric parameters of the tissue simulants were measured every day using the dielectric probe kit and the network analyser. A system check measurement was made following the determination of the dielectric parameters of the

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simulant, using the dipole validation kit. A power level of 250 mW was supplied to the dipole antenna, which was placed under the flat section of the twin SAM phantom. The system checking results (dielectric parameters and SAR values) are given in the table below.

System checking, head tissue simulant

		SAR [W/kg],	Dielectric Parameters		Temp
f [MHz]	Description	1 g	€r	σ [S/m]	[°C]
	Reference result	2.39	40.2	0.88	
	$\pm10\%$ window	2.15 - 2.63			
835	2010-03-18	2.32	40.9	0.87	21.6

Plots of the system checking scans are given in Appendix A.

4.3.3 Tissue Simulants used in the Measurements

Head tissue simulant measurements

f		Dielectric Parameters		Temp
[MHz]	Description	εr	σ [S/m]	[°C]
	Recommended value	41.5	0.90	
	± 5% window	39.4 – 43.6	0.86 - 0.95	
836	2010-03-18	40.9	0.87	21.6

Body tissue simulant measurements

body dissac similarite in casar ciricitis						
f		Dielectric F	Temp			
[MHz]	Description	εr	σ [S/m]	[°C]		
	Recommended value	55.2	0.97			
	\pm 5% window	52.4 – 58.0	0.92 – 1.02			
836	2010-03-18	53.0	0.96	21.0		





5. DESCRIPTION OF THE TEST PROCEDURE

5.1 Device Holder

The device was placed in the device holder (illustrated below) that is supplied by SPEAG as an integral part of the Dasy system.



Device holder supplied by SPEAG

A Nokia designed spacer (illustrated below) was used to position the device within the SPEAG holder. The spacer positions the device so that the holder has minimal effect on the test results but still holds the device securely. The spacer was removed before the tests.



Nokia spacer

5.2 Test Positions

5.2.1 Against Phantom Head

Measurements were made in "cheek" and "tilt" positions on both the left hand and right hand sides of the phantom.

The positions used in the measurements were according to IEEE 1528 - 2003 "IEEE Recommended Practice for Determining the Peak Spatial-Average Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques".

5.2.2 Body Worn Configuration

The device was placed in the SPEAG holder using the Nokia spacer and placed below the flat section of the phantom. The distance between the device and the phantom was kept at the separation distance indicated in Section 1.2.2 using a separate flat spacer that was removed





before the start of the measurements. The device was oriented with its back facing the phantom since this orientation gives higher results.

5.3 Scan Procedures

First, area scans were used for determination of the field distribution. Next, a zoom scan, a minimum of 5x5x7 points covering a volume of at least 30x30x30mm, was performed around the highest E-field value to determine the averaged SAR value. Drift was determined by measuring the same point at the start of the area scan and again at the end of the zoom scan.

5.4 SAR Averaging Methods

The maximum SAR value was averaged over a cube of tissue using interpolation and extrapolation.

The interpolation, extrapolation and maximum search routines within Dasy4 are all based on the modified Quadratic Shepard's method (Robert J. Renka, "Multivariate Interpolation Of Large Sets Of Scattered Data", University of North Texas ACM Transactions on Mathematical Software, vol. 14, no. 2, June 1988, pp. 139-148).

The interpolation scheme combines a least-square fitted function method with a weighted average method. A trivariate 3-D / bivariate 2-D quadratic function is computed for each measurement point and fitted to neighbouring points by a least-square method. For the zoom scan, inverse distance weighting is incorporated to fit distant points more accurately. The interpolating function is finally calculated as a weighted average of the quadratics.

In the zoom scan, the interpolation function is used to extrapolate the Peak SAR from the deepest measurement points to the inner surface of the phantom.





6. MEASUREMENT UNCERTAINTY

Table 6.1 – Measurement uncertainty evaluation

Uncertainty Componentin IEEE 1528Measurement SystemE2.1Probe CalibrationE2.1Axial IsotropyE2.2Hemispherical IsotropyE2.2Boundary EffectE2.3LinearityE2.4System Detection LimitsE2.5Readout ElectronicsE2.6Response TimeE2.7Integration TimeE2.8RF Ambient Conditions - NoiseE6.1RF Ambient Conditions - ReflectionsE6.1Probe Positioner Mechanical ToleranceE6.2Probe Positioning with respect to Phantom ShellE6.3Extrapolation, interpolation and Integration Algorithms for Max. SARE5EvaluationE5Test Sample RelatedE4.2Device Holder UncertaintyE4.1	±5.9 ±4.7 ±9.6 ±1.0 ±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	Prob Dist	$ \begin{array}{c} 1 \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	1 (1-c _p) ^{1/2} (c _p) ^{1/2} 1 1 1 1	±5.9 ±1.9 ±3.9 ±0.6 ±2.7 ±0.6	 V₁ ∞ ∞ ∞ ∞ ∞ ∞ ∞
Probe Calibration E2.1 Axial Isotropy E2.2 Hemispherical Isotropy E2.2 Boundary Effect E2.3 Linearity E2.4 System Detection Limits E2.5 Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise E6.1 RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation E4.2 Device Holder Uncertainty E4.1	±4.7 ±9.6 ±1.0 ±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R R R R N R	$ \begin{array}{c} \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	(1-c _p) ^{1/2} (c _p) ^{1/2} 1 1 1 1	±1.9 ±3.9 ±0.6 ±2.7 ±0.6 ±1.0	∞ ∞ ∞ ∞
Axial Isotropy Hemispherical Isotropy E2.2 Boundary Effect E2.3 Linearity E2.4 System Detection Limits E2.5 Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise RF Ambient Conditions - Reflections Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E2.2 E2.3 E2.4 E2.5 E2.6 Response Time E2.7 Integration Time E2.8 E6.1 RF Ambient Conditions - Noise E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty	±4.7 ±9.6 ±1.0 ±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R R R R N R	$ \begin{array}{c} \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \\ 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	(1-c _p) ^{1/2} (c _p) ^{1/2} 1 1 1 1	±1.9 ±3.9 ±0.6 ±2.7 ±0.6 ±1.0	∞ ∞ ∞ ∞
Hemispherical Isotropy Boundary Effect E2.3 Linearity E2.4 System Detection Limits E2.5 Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise RF Ambient Conditions - Reflections Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E2.3 E2.4 E2.5 E2.6 Readout Electronics E2.6 Readout Electronics E2.7 Integration Time E2.8 E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty	±9.6 ±1.0 ±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R R R N R	$ \begin{array}{c} \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \end{array} $ $ \begin{array}{c} \sqrt{3} \\ \sqrt{3} \end{array} $ $ \begin{array}{c} 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	(C _P) ^{1/2} 1 1 1 1 1 1	±3.9 ±0.6 ±2.7 ±0.6 ±1.0	8 8
Boundary Effect E2.3 Linearity E2.4 System Detection Limits E2.5 Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise E6.1 RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation E5.5 Evaluation E4.2 Device Holder Uncertainty E4.1	±1.0 ±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R R N R	$ \begin{array}{c} \sqrt{3} \\ \sqrt{3} \\ \sqrt{3} \end{array} $ $ \begin{array}{c} 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	1 1 1 1 1	±0.6 ±2.7 ±0.6 ±1.0	& & &
Linearity E2.4 System Detection Limits E2.5 Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise E6.1 RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1	±4.7 ±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R N R R	$ \begin{array}{c c} \sqrt{3} \\ \sqrt{3} \\ 1 \\ \sqrt{3} \\ \sqrt{3} \end{array} $	1 1 1 1	±2.7 ±0.6 ±1.0	∞ ∞
System Detection Limits Readout Electronics Response Time Integration Time E2.8 RF Ambient Conditions - Noise RF Ambient Conditions - Reflections Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty	±1.0 ±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R N R R	√3 1 √3 √3	1 1 1	±0.6 ±1.0	∞
Readout Electronics E2.6 Response Time E2.7 Integration Time E2.8 RF Ambient Conditions - Noise E6.1 RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1	±1.0 ±0.8 ±2.6 ±3.0 ±3.0 ±0.4	N R R R	1 √3 √3	1 1	±1.0	
Response Time E2.8 Integration Time E2.8 RF Ambient Conditions - Noise E6.1 RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance E6.2 Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR E5 Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1	±0.8 ±2.6 ±3.0 ±3.0 ±0.4	R R R	√3 √3	1		∞
Integration Time RF Ambient Conditions - Noise RF Ambient Conditions - Reflections Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E6.1 E6.2 E6.3 E5.	±2.6 ±3.0 ±3.0 ±0.4	R R	√3		⊥ 0 5	
RF Ambient Conditions - Noise RF Ambient Conditions - Reflections E6.1 Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E6.1 E6.2 E6.2 E6.3 E6.3 E6.3 E6.3 E6.3 E6.3 E6.3 E6.3	±3.0 ±3.0 ±0.4	R		1	±0.5	∞
RF Ambient Conditions - Reflections Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E6.1 E6.2 E6.3 E5.	±3.0 ±0.4		1-	T	±1.5	∞
Probe Positioner Mechanical Tolerance Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E6.2 E6.3 E7.3 E8.3 E9.3 E9.	±0.4	Ь	√3	1	±1.7	∞
Probe Positioning with respect to Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E6.3 E6.3 E6.3		R	√3	1	±1.7	∞
Phantom Shell Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty E0.3 E5. E5. E5. E4.2 E4.2		R	√3	1	±0.2	∞
Extrapolation, interpolation and Integration Algorithms for Max. SAR Evaluation Test sample Related Test Sample Positioning Device Holder Uncertainty Extrapolation and Extra	± 2.9	R	√3	1	±1.7	∞
Integration Algorithms for Max. SAR E5 Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1	±2.9	IX.	٧,5	1		$\stackrel{\sim}{ }$
Evaluation Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1						
Test sample Related Test Sample Positioning E4.2 Device Holder Uncertainty E4.1	±3.9	R	√3	1	±2.3	∞
Test Sample Positioning E4.2 Device Holder Uncertainty E4.1						
Device Holder Uncertainty E4.1						
-	±6.0	N	1	1	±6.0	11
	±5.0	N	1	1	±5.0	7
Output Power Variation - SAR drift 6.6.3	± 0.0	R	√3	1	±0.0	∞
measurement						
Phantom and Tissue Parameters						
Phantom Uncertainty (shape and	. 4.0	D	./>	1		
thickness tolerances)	±4.0	R	√3	1	±2.3	∞
Conductivity Target - tolerance E3.2	±5.0	R	√3	0.64	±1.8	∞
Conductivity - measurement uncertainty E3.3	±5.5	N	1	0.64	±3.5	5
Permittivity Target - tolerance E3.2	±5.0	R	√3	0.6	±1.7	∞
Permittivity - measurement uncertainty E3.3	±2.9	N	1	0.6	±1.7	5
Combined Standard Uncertainty		RSS			±12.9	116
Coverage Factor for 95%						
Expanded Uncertainty	-				±25.8	





7. RESULTS

The measured Head SAR values for the test device are tabulated below:

CDMA800 Head SAR results

			SAR, av	eraged over 1g	(W/kg)
Mode	Test configuration		Ch 1013 824.70 MHz	Ch 384 836.52 MHz	Ch 777 848.31 MHz
RC3 / S055	Power		24.19 dBm	24.12 dBm	24.11 dBm
	Left	Cheek	0.672	0.838	0.773
		Tilt	-	0.473	-
	Right	Cheek	0.685	0.830	0.782
		Tilt	-	0.449	-

The measured Body SAR values for the test device are tabulated below:

CDMA800 Body SAR results

			SAR, averaged over 1g (W/kg)			
Mode	e Option used Test configuration		Ch 1013 824.70 MHz	Ch 384 836.52 MHz	Ch 777 848.31 MHz	
RC3 / S055		Power	24.19 dBm	24.12 dBm	24.11 dBm	
	Display facing phantom Back facing phantom	Without headset	-	-	-	
		Headset HS-105	-	-	-	
		Without headset	1.04	0.946	0.895	
		Headset HS-105	0.648	0.810	0.763	

Plots of the Measurement scans are given in Appendix B.





APPENDIX A: SYSTEM CHECKING SCANS





Date/Time: 2010-03-18 9:38:07 AM

Test Laboratory: TCC Nokia Type: D835V2; Serial: 479

Communication System: CW835 Frequency: 835 MHz; Duty Cycle: 1:1

Medium: Head 835; Medium Notes: Medium Temperature: t= 21.6 C

Medium parameters used: f = 835 MHz; σ = 0.869 mho/m; ε_r = 40.9; ρ = 1000 kg/m³

Phantom section: Flat Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(6.19, 6.19, 6.19); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM3; Type: SAM; Serial: TP-1427
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

d=15mm, Pin=250mW/Area Scan (61x121x1): Measurement grid: dx=10mm, dy=10mm

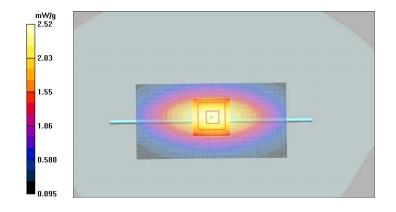
Maximum value of SAR (interpolated) = 2.52 mW/g

d=15mm, Pin=250mW/Zoom Scan (7x7x7) (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 55.5 V/m Peak SAR (extrapolated) = 3.42 W/kg

SAR(1 g) = 2.32 mW/g SAR(10 g) = 1.52 mW/g Power Drift = -0.038 dB

Maximum value of SAR (measured) = 2.51 mW/g







APPENDIX B: MEASUREMENT SCANS





Date/Time: 2010-03-18 10:12:38 AM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 836.52 MHz; Duty Cycle: 1:1

Medium: Head 835; Medium Notes: Medium Temperature: t= 21.6 C

Medium parameters used: f = 837 MHz; σ = 0.869 mho/m; ε_r = 40.8; ρ = 1000 kg/m³

Phantom section: Left Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(6.19, 6.19, 6.19); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM3; Type: SAM; Serial: TP-1427
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

Cheek position - Middle/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm

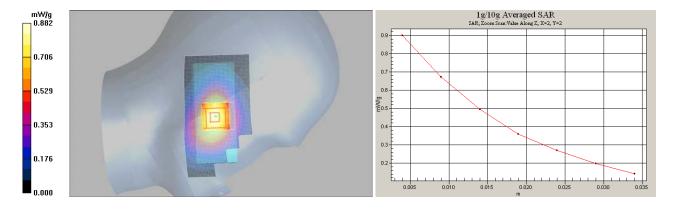
Maximum value of SAR (interpolated) = 0.882 mW/g

Cheek position - Middle/Zoom Scan (5x5x7)/Cube 0: Measurement grid: dx=7.5mm, dy=7.5mm, dz=5mm

Reference Value = 11.9 V/m
Peak SAR (extrapolated) = 1.11 W/kg
SAR(1 g) = 0.838 mW/g

SAR(10 g) = 0.579 mW/g Power Drift = -0.341 dB

Maximum value of SAR (measured) = 0.899 mW/g







Date/Time: 2010-03-18 10:50:10 AM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 836.52 MHz; Duty Cycle: 1:1

Medium: Head 835; Medium Notes: Medium Temperature: t= 21.6 C

Medium parameters used: f = 837 MHz; $\sigma = 0.869$ mho/m; $\varepsilon_r = 40.8$; $\rho = 1000$ kg/m³

Phantom section: Left Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(6.19, 6.19, 6.19); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection (Locations From Previous Scan Used))Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM3; Type: SAM; Serial: TP-1427
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

Tilt position - Middle/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm

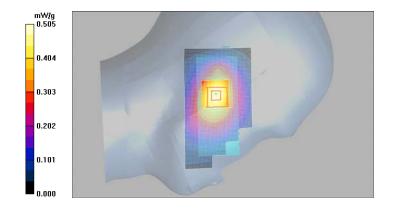
Maximum value of SAR (interpolated) = 0.505 mW/g

Tilt position - Middle/Zoom Scan (5x5x7)/Cube 0: Measurement grid: dx=7.5mm, dy=7.5mm, dz=5mm

Reference Value = 15.7 V/m
Peak SAR (extrapolated) = 0.609 W/kg

SAR(1 g) = 0.473 mW/g SAR(10 g) = 0.338 mW/g Power Drift = -0.107 dB

Maximum value of SAR (measured) = 0.503 mW/g







Date/Time: 2010-03-18 11:02:21 AM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 836.52 MHz; Duty Cycle: 1:1

Medium: Head 835; Medium Notes: Medium Temperature: t= 21.6 C

Medium parameters used: f = 837 MHz; σ = 0.869 mho/m; ε_r = 40.8; ρ = 1000 kg/m³

Phantom section: Right Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(6.19, 6.19, 6.19); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM3; Type: SAM; Serial: TP-1427
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

Cheek position - Middle/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm

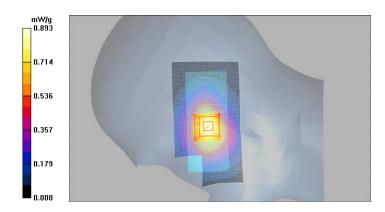
Maximum value of SAR (interpolated) = 0.893 mW/g

Cheek position - Middle/Zoom Scan (5x5x7)/Cube 0: Measurement grid: dx=7.5mm, dy=7.5mm, dz=5mm

Reference Value = 11.1 V/m
Peak SAR (extrapolated) = 1.13 W/kg
SAR(1 g) = 0.830 mW/g

SAR(10 g) = 0.572 mW/g Power Drift = 0.226 dB

Maximum value of SAR (measured) = 0.904 mW/g







Date/Time: 2010-03-18 11:41:27 AM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 836.52 MHz; Duty Cycle: 1:1

Medium: Head 835; Medium Notes: Medium Temperature: t= 21.6 C

Medium parameters used: f = 837 MHz; $\sigma = 0.869$ mho/m; $\varepsilon_r = 40.8$; $\rho = 1000$ kg/m³

Phantom section: Right Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(6.19, 6.19, 6.19); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection (Locations From Previous Scan Used))Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM3; Type: SAM; Serial: TP-1427
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

Tilt position - Middle/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm

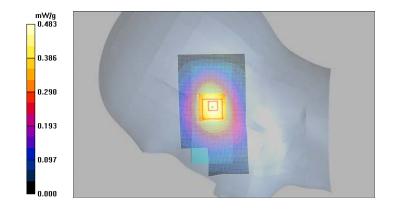
Maximum value of SAR (interpolated) = 0.483 mW/g

Tilt position - Middle/Zoom Scan (5x5x7)/Cube 0: Measurement grid: dx=7.5mm, dy=7.5mm, dz=5mm

Reference Value = 14.5 V/m
Peak SAR (extrapolated) = 0.580 W/kg
SAR(1 g) = 0.449 mW/g

SAR(10 g) = 0.323 mW/g Power Drift = -0.040 dB

Maximum value of SAR (measured) = 0.471 mW/g







Date/Time: 2010-03-18 1:54:34 PM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 824.7 MHz; Duty Cycle: 1:1

Medium: Body 835; Medium Notes: Medium Temperature: t= 21.0 C

Medium parameters used: f = 825 MHz; $\sigma = 0.953$ mho/m; $\varepsilon_r = 53.2$; $\rho = 1000$ kg/m³

Phantom section: Flat Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(5.91, 5.91, 5.91); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection (Locations From Previous Scan Used))Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480; Calibrated: 2009-09-15
- Phantom: SAM1; Type: SAM; Serial: TP 01097
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

Body - Low - No Accessory - Back facing phantom/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm

Maximum value of SAR (interpolated) = 1.11 mW/g

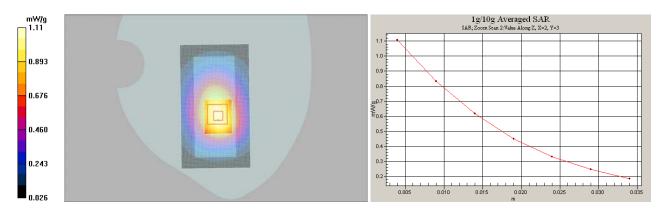
Body - Low - No Accessory - Back facing phantom/Zoom Scan 2 (5x6x7)/Cube 0: Measurement grid: dx=7.5mm,

dy=7.5mm, dz=5mm Reference Value = 16.3 V/m

Peak SAR (extrapolated) = 1.34 W/kg

SAR(1 g) = 1.04 mW/g SAR(10 g) = 0.749 mW/g Power Drift = 0.000 dB

Maximum value of SAR (measured) = 1.10 mW/g







Date/Time: 2010-03-18 2:58:37 PM

Test Laboratory: TCC Nokia

Type: RM-685; Serial: A0000001C8FB23

Communication System: CDMA800 Frequency: 836.52 MHz; Duty Cycle: 1:1

Medium: Body 835; Medium Notes: Medium Temperature: t= 21.0 C

Medium parameters used: f = 837 MHz; σ = 0.963 mho/m; ϵ_r = 53; ρ = 1000 kg/m³

Phantom section: Flat Section

DASY4 Configuration:

- Probe: ET3DV6 SN1652; Probe Notes:
- ConvF(5.91, 5.91, 5.91); Calibrated: 2009-09-21
- Sensor-Surface: 4mm (Mechanical Surface Detection (Locations From Previous Scan Used))Sensor-Surface: 4mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn480: Calibrated: 2009-09-15
- Phantom: SAM1; Type: SAM; Serial: TP 01097
- Measurement SW: DASY4, V4.7 Build 71; Postprocessing SW: SEMCAD, V1.8 Build 186

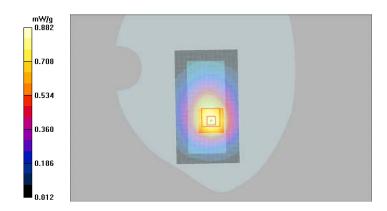
Body - Middle - HS-105 - Back facing phantom/Area Scan (51x91x1): Measurement grid: dx=15mm, dy=15mm Maximum value of SAR (interpolated) = 0.882 mW/g

Body - Middle - HS-105 - Back facing phantom/Zoom Scan (5x5x7)/Cube 0: Measurement grid: dx=7.5mm, dy=7.5mm, dz=5mm

Reference Value = 11.3 V/m Peak SAR (extrapolated) = 1.07 W/kg

SAR(1 g) = 0.810 mW/g SAR(10 g) = 0.569 mW/g Power Drift = -0.007 dB

Maximum value of SAR (measured) = 0.868 mW/g







APPENDIX C: CONDUCTED POWER MEASUREMENTS FOR SUPPORTED TRANSMISSION MODES

Type: RM-685; Serial number: A0000001C8FB23

CDMA800

	CDM	A8UU	Cl 4042	Cl 204	cl 777
	Service Options and Channel		Ch 1013	Ch 384	Ch 777
Radio Configuration	Configurations	Supported	824.70 MHz	836.52 MHz	848.31 MHz
			Pavg dBm	Pavg dBm	Pavg dBm
RC1	S01	No	-	-	-
RC1	S02	Yes	24.17	24.07	24.04
RC1	S03	Yes	24.16	24.10	24.12
RC1	S055	Yes	24.18	24.10	24.07
RC2	S09	Yes	24.12	24.04	24.01
RC2	S017	Yes	24.15	24.14	24.11
RC2	S055	Yes	24.11	24.05	24.02
RC3	S01	No	-	-	-
RC3	S02	Yes	24.19	24.12	24.10
RC3	S03	Yes	24.16	24.03	24.02
RC3	S032 (no SCH1)	Yes	24.20	24.13	24.12
RC3	S032 (SCH1 9.6kbps)	Yes	24.22	24.16	24.11
RC3	S032 (SCH1 19.2kbps)	Yes	24.21	24.12	24.13
RC3	S032 (SCH1 38.4kbps)	Yes	24.23	24.15	24.12
RC3	S032 (SCH1 76.8kbps)	Yes	24.22	24.16	24.12
RC3	S032 (SCH1 153.6kbps)	Yes	24.26	24.15	24.11
RC3	S033 (SCH1 9.6kbps)	No	-	-	-
RC3	S033 (SCH1 19.2kbps)	No	-	-	-
RC3	S033 (SCH1 38.4kbps)	No	-	-	-
RC3	S033 (SCH1 76.8kbps)	No	-	-	-
RC3	S033 (SCH1 153.6kbps)	No	-	-	-
RC3	S055	Yes	24.19	24.12	24.11
RC4	S01	No	-	-	-
RC4	S02	Yes	24.19	24.13	24.09
RC4	S03	Yes	24.15	24.05	24.00
RC4	S032 (no SCH1)	Yes	24.25	24.14	24.10
RC4	S032 (SCH1 9.6kbps)	Yes	24.24	24.14	24.10
RC4	S032 (SCH1 19.2kbps)	Yes	24.24	24.15	24.08
RC4	S032 (SCH1 38.4kbps)	Yes	24.23	24.12	24.10
RC4	S032 (SCH1 76.8kbps)	Yes	24.23	24.14	24.10
RC4	S032 (SCH1 153.6kbps)	Yes	24.24	24.17	24.11
RC4	S033 (SCH1 9.6kbps)	No	-	-	-
RC4	S033 (SCH1 19.2kbps)	No	-	-	-
RC4	S033 (SCH1 38.4kbps)	No	-	-	-
RC4	S033 (SCH1 76.8kbps)	No	_	-	-
RC4	S033 (SCH1 153.6kbps)	No	_	-	-
RC4	S055	Yes	24.18	24.11	24.08
I.C.I	3033	1.03		L 11+±±	

SAR Report FCC_RM-685_01 Applicant: Nokia Corporation Type: RM-685

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RC5	S09	Yes	24.24	24.10	24.08
RC5	5017	Yes	24.14	24.04	23.98
RC5	S033 (SCH1 9.6kbps)	No	-	-	-
RC5	S033 (SCH1 19.2kbps)	No	-	-	-
RC5	S033 (SCH1 38.4kbps)	No	-	-	-
RC5	S033 (SCH1 76.8kbps)	No	-	-	-
RC5	S033 (SCH1 153.6kbps)	No	-	-	-
RC5	S055	Yes	24.22	24.12	24.11





APPENDIX D: RELEVANT PAGES FROM PROBE CALIBRATION REPORT(S)

See the following pages.

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Client

Nokia Beijing TCC

Certificate No: ET3-1652 Sep09

Accreditation No.: SCS 108

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CALIBRATION CERTIFICATE

Object ET3DV6 - SN:1652

Calibration procedure(s) QA CAL-01.v6, QA CAL-23.v3 and QA CAL-25.v2

Calibration procedure for dosimetric E-field probes

Calibration date: September 21, 2009

Condition of the calibrated item In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	1-Apr-09 (No. 217-01030)	Apr-10
Power sensor E4412A	MY41495277	1-Apr-09 (No. 217-01030)	Apr-10
Power sensor E4412A	MY41498087	1-Apr-09 (No. 217-01030)	Apr-10
Reference 3 dB Attenuator	SN: S5054 (3c)	31-Mar-09 (No. 217-01026)	Mar-10
Reference 20 dB Attenuator	SN: S5086 (20b)	31-Mar-09 (No. 217-01028)	Mar-10
Reference 30 dB Attenuator	SN: S5129 (30b)	31-Mar-09 (No. 217-01027)	Mar-10
Reference Probe ES3DV2	SN: 3013	2-Jan-09 (No. ES3-3013_Jan09)	Jan-10
DAE4	SN: 660	9-Sep-08 (No. DAE4-660_Sep08)	Sep-09
Secondary Standards	ID#	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Oct-07)	In house check: Oct-09
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-08)	In house check: Oct-09
	Name	Function	Signature
Calibrated by:	Jeton Kastrati	Laboratory Technician	7=U
Approved by:	Katja Pokovic	Technical Manager	1 20 W

Issued: September 21, 2009

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

DASY - Parameters of Probe: ET3DV6 SN:1652

Sensitivity in Free Space ^A	Diode Compression ^B
--	--------------------------------

NormX	2.00 ± 10.1%	$\mu V/(V/m)^2$	DCP X	94 mV
NormY	2.07 ± 10.1%	$\mu V/(V/m)^2$	DCP Y	94 mV
NormZ	1.97 ± 10.1%	$\mu V/(V/m)^2$	DCP Z	93 mV

Sensitivity in Tissue Simulating Liquid (Conversion Factors)

Please see Page 8.

Boundary Effect

TSL 835 MHz Typical SAR gradient: 5 % per mm

Sensor Cente	r to Phantom Surface Distance	3.7 mm	4.7 mm
SAR _{be} [%]	Without Correction Algorithm	10.1	5.9
SAR _{be} [%]	With Correction Algorithm	0.8	0.5

TSL 1750 MHz Typical SAR gradient: 10 % per mm

Sensor Cente	r to Phantom Surface Distance	3.7 mm	4.7 mm
SAR _{be} [%]	Without Correction Algorithm	10.0	5.5
SAR _{be} [%]	With Correction Algorithm	0.9	0.6

Sensor Offset

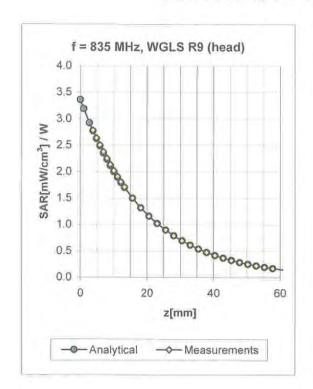
Probe Tip to Sensor Center 2.7 mm

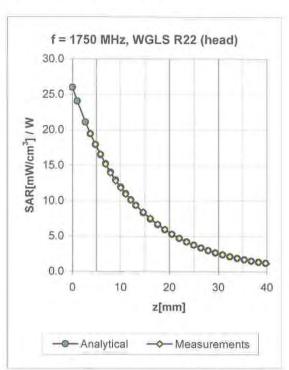
The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

A The uncertainties of NormX,Y,Z do not affect the E2-field uncertainty inside TSL (see Page 8).

⁸ Numerical linearization parameter, uncertainty not required.

Conversion Factor Assessment





f [MHz]	Validity [MHz] ^c	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
835	± 50 / ± 100	Head	41.5 ± 5%	0.90 ± 5%	0.66	1.85	6.19 ± 11.0% (k=2)
1750	± 50 / ± 100	Head	40.1 ± 5%	1.37 ± 5%	0.54	2.64	5.15 ± 11.0% (k=2)
1900	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.68	2.31	4.91 ± 11.0% (k=2)
1950	± 50 / ± 100	Head	40.0 ± 5%	1.40 ± 5%	0.71	2.27	4.76 ± 11.0% (k=2)
2450	± 50 / ± 100	Head	39.2 ± 5%	1.80 ± 5%	0.99	1.70	4.33 ± 11.0% (k=2)
835	± 50 / ± 100	Body	55.2 ± 5%	0.97 ± 5%	0.48	2.24	5.91 ± 11.0% (k=2)
1750	±50/±100	Body	53.4 ± 5%	1.49 ± 5%	0.65	3.14	4.65 ± 11.0% (k=2)
1900	± 50 / ± 100	Body	53.3 ± 5%	1.52 ± 5%	0.83	2.58	4.44 ± 11.0% (k=2)
1950	±50/±100	Body	53.3 ± 5%	1.52 ± 5%	0.99	2.27	4.54 ± 11.0% (k=2)
2450	± 50 / ± 100	Body	52.7 ± 5%	1.95 ± 5%	0.99	1.71	4.08 ± 11.0% (k=2)

^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.





APPENDIX E: RELEVANT PAGES FROM DIPOLE VALIDATION KIT REPORT(S)

See the following pages.

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
Service suisse d'étalonnage
Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Client

Nokia SD TCC

Certificate No: D835V2-479 Feb09

CALIBRATION CERTIFICATE

Object D835V2 - SN: 479

Calibration procedure(s) QA CAL-05.v7

Calibration procedure for dipole validation kits

Calibration date: February 09, 2009

Condition of the calibrated item In Tolerance

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).

The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter EPM-442A	GB37480704	08-Oct-08 (No. 217-00898)	Oct-09
Power sensor HP 8481A	US37292783	08-Oct-08 (No. 217-00898)	Oct-09
Reference 20 dB Attenuator	SN: 5086 (20g)	01-Jul-08 (No. 217-00864)	Jul-09
Type-N mismatch combination	SN: 5047.2 / 06327	01-Jul-08 (No. 217-00867)	Jul-09
Reference Probe ES3DV2	SN: 3025	28-Apr-08 (No. ES3-3025_Apr08)	Apr-09
DAE4	SN: 601	14-Mar-08 (No. DAE4-601_Mar08)	Mar-09
Secondary Standards	ID#	Check Date (in house)	Scheduled Check
Power sensor HP 8481A	MY41092317	18-Oct-02 (in house check Oct-07)	In house check: Oct-09
RF generator R&S SMT-06	100005	4-Aug-99 (in house check Oct-07)	In house check: Oct-09
Network Analyzer HP 8753E	US37390585 S4206	18-Oct-01 (in house check Oct-08)	In house check: Oct-09
	Name	Function	Signature
Calibrated by:	Jeton Kastrati	Laboratory Technician	7=10-
Approved by:	Katja Pokovic	Technical Manager	1 2C - M

Issued: February 10, 2009

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

DASY5 Validation Report for Head TSL

Date/Time: 03.02.2009 10:04:18

Test Laboratory: SPEAG, Zurich, Switzerland

DUT: Dipole 835 MHz; Type: D835V2; Serial: D835V2 - SN:479

Communication System: CW-835; Frequency: 835 MHz; Duty Cycle: 1:1

Medium: HSL 900 MHz

Medium parameters used: f = 835 MHz; $\sigma = 0.88$ mho/m; $\varepsilon_r = 40.2$; $\rho = 1000$ kg/m³

Phantom section: Flat Section

Measurement Standard: DASY5 (IEEE/IEC)

DASY5 Configuration:

Probe: ES3DV2 - SN3025; ConvF(5.97, 5.97, 5.97); Calibrated; 28.04.2008

Sensor-Surface: 3.4mm (Mechanical Surface Detection)

Electronics: DAE4 Sn601; Calibrated: 14.03,2008

Phantom: Flat Phantom 4.9L; Type: QD000P49AA; Serial: 1001

Measurement SW: DASY5, V5.0 Build 120; SEMCAD X Version 13.4 Build 45

Pin=250mW; dip=15mm; dist=3.4mm/Zoom Scan (7x7x7)/Cube 0: Measurement grid:

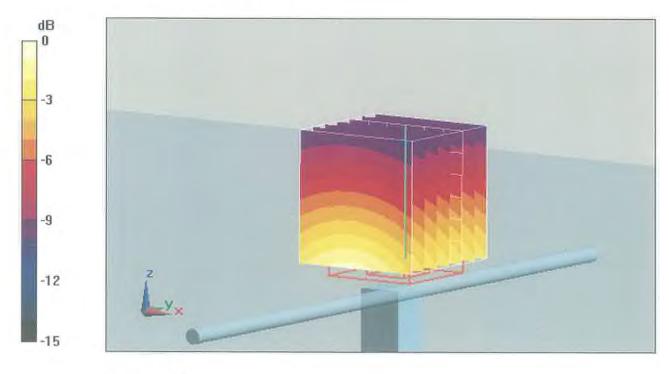
dx=5mm, dy=5mm, dz=5mm

Reference Value = 56.4 V/m; Power Drift = -0.011 dB

Peak SAR (extrapolated) = 3.51 W/kg

SAR(1 g) = 2.39 mW/g; SAR(10 g) = 1.58 mW/g

Maximum value of SAR (measured) = 2.7 mW/g



0 dB = 2.7 mW/g

Certificate No: D835V2-479_Feb09